



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/036,140	MCCLELLAN ET AL.	
Examiner	Art Unit	
Ji-Yong D. Chung	2143	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East (Updated search)	3/5/2006	JDC	
STIC Search report (Fast and Focused. See attached)	3/2/2006	JDC	
Double patenting search	3/2/2006	JDC	